Massachusetts Institute of Technology Department of Electrical Engineering and Computer Science

6.002 – Circuits and Electronics Spring 2003

Handout S03-019 - Lab #1: Thevenin/Norton Equivalents & Logic Gates

Introduction

This lab has two independent parts, each with pre-lab, in-lab and post-lab exercises. The first part explores the characterization of a network by its Thevenin and Norton equivalents. The second part explores the static behavior of logic gates constructed with n-channel MOSFETs and resistors. You should complete the pre-lab exercises in your lab notebook before coming to lab. Then, carry out the in-lab exercises on your assigned lab day between February 24 and February 28. After completing the in-lab exercises, have a TA or LA check your work and sign your lab notebook. Finally, complete the post-lab exercises in your lab notebook, and turn in your lab notebook during recitation on Monday March 10.

Pre-Lab Exercises

Pre-Lab Exercises 1-1 and 1-2 explore the characterization of a network by its Thevenin and Norton equivalents. Pre-Lab Exercises 1-3 through 1-5 explore the static behavior of logic gates.

- (1-1) Determine the Thevenin and Norton equivalents of the network shown in Figure 1 as viewed at its port.
- (1-2) Evaluate the Thevenin and Norton equivalents of the network for the following values: V = 5 V; $R_1 = 50 \Omega$; $R_2 = 2.2 \text{ k}\Omega$; $R_3 = 1.5 \text{ k}\Omega$.
- (1-3) Figure 2 shows a NOT gate, or inverter, a NOR gate and a NAND gate constructed from n-channel MOSFETs and 1 k Ω resistors. The figure also shows a switch-resistor model for the n-channel MOSFET. Using the switch-resistor model, compute $v_{\rm OUT}$ for all three gates. In doing so, consider all combinations of input voltages; an input voltage may be either above or below the MOSFET threshold voltage $v_{\rm T}$. In each case, evaluate $v_{\rm OUT}$ assuming $R_{\rm DS-ON}=4~\Omega$. Summarize your results for each gate in a table.
- (1-4) Figure 3 shows a combinational logic circuit. Determine the input-output truth table for this circuit.

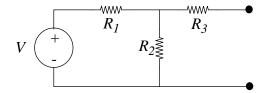


Figure 1: source-resistor network for Pre-Lab Exercises 1-1 and 1-2.

(1-5) Draw the circuit diagram for the combinational logic circuit shown in Figure 3 using the gates shown in Figure 2.

In-Lab Exercises

In-Lab Exercises 1-1 through 1-3 explore the characterization of a network by its Thevenin and Norton equivalents. In-Lab exercises 1-4 through 1-9 explore the static behavior of logic gates.

- (1-1) Construct the network shown in Figure 4. However, before connecting the signal generator to the remainder of the network, set its output voltage to a constant 5 V, and check this output with the multi-meter. Note that the network is the same as that shown in Figure 1, with the function generator serving as both the voltage source and resistor R_1 .
- (1-2) Measure the open-circuit voltage and short-circuit current of the network with the multi-

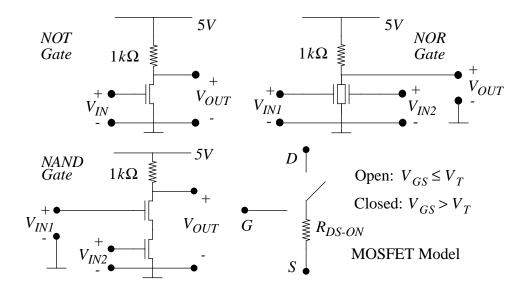


Figure 2: a NOT gate, a NOR gate, a NAN gate, and the switch-resistor MOSFET model.

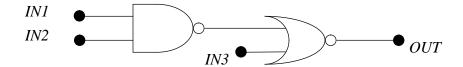


Figure 3: combinational logic circuit for Pre-Lab Exercises 1-4 and 1-5.

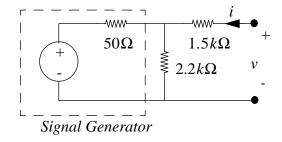


Figure 4: experimental source-resistor network.

meter. Note that the multi-meter is itself a near open circuit when used as a voltmeter, and a near short circuit when used as an ammeter. Therefore, the direct connection of the multi-meter across the port implements the proper measurement in both cases. Your results from Pre-Lab Exercise 1-2 should show that both measurements are within the safe range for the multi-meter.

- (1-3) Connect a resistor across the port of the network and measure the port voltage v with the multi-meter. Do so for resistors having resistances of 560 Ω , 1 k Ω and 2.2 k Ω .
- (1-4) Construct the circuit shown in Figure 5, which is designed to measure the threshold voltage of the MOSFET; the MOSFET the pin assignments are given in the attached data sheet. Use the multi-meter to measure $v_{\rm GS}$ and the oscilloscope to measure $v_{\rm DS}$, and set the signal generator to provide a constant output. With $v_{\rm GS}$ at 0 V, $v_{\rm DS}$ should be at 5 V. Gradually increase $v_{\rm GS}$ until $v_{\rm DS}$ starts to fall. The value of $v_{\rm GS}$ at which this occurs is $v_{\rm T}$. Caution: avoid handling the MOSFET by its leads because it can be damaged by static electricity.
- (1-5) Beginning with the circuit shown in Figure 5, disconnect the 1 k Ω resistor and the oscilloscope from the MOSFET drain. With $v_{\rm GS}$ at 5 V, measure $R_{\rm DS}$ with the multi-meter. This resistance is $R_{\rm DS-ON}$ for $v_{\rm GS}=5$ V; note that the multi-meter supplies a very small voltage when used as an ohmmeter.
- (1-6) Construct the NOT gate from Figure 2 and connect its input to a switch and $10 \text{ k}\Omega$ resistor as shown in Figure 6. For both switch positions, that is for both logic input levels to the gate, measure v_{OUT} with the multi-meter.

The switch pack and the 10 k Ω resistor array have been chosen to simplify the wiring of the switches to their associated resistors. Specifically, the switch pack can be placed in the protoboard so that one side is on a common ground strip and each pin on the other side is on a separate trace. Then, the resistor pack can be inserted into the protoboard along side the switch pack so that separate resistors connect to each switch. Finally, the common pin of the resistor pack can be connected to the 5 V power supply through a single wire. Caution: the switch-pack pins are fragile, and they can also pop out of the protoboard.

(1-7) Construct the NOR gate from Figure 2. As for the NOT gate shown in Figure 6, connect the inputs to the NOR gate to switches and 10 k Ω resistors. For all combinations of switch positions, that is for all combinations of logic input levels to the gate, measure v_{OUT} with

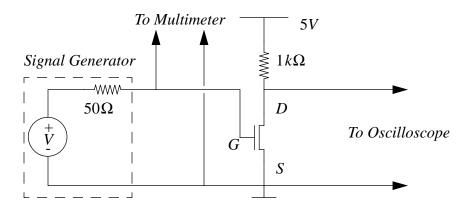


Figure 5: circuit to measure $v_{\rm T}$.

- the multi-meter. Save the NOR gate for In-Lab Exercise 1-9.
- (1-8) Repeat In-Lab Exercise 1-7 for the NAND gate. Save the NAND gate for In-Lab Exercise 1-9.
- (1-9) Use the NOR gate and NAND gate to implement the combinational logic circuit of Figure 3, as outlined in Pre-Lab Exercise 1-5. Connect each input to a switch and resistor as in In-Lab Exercises 1-6 through 1-8. By changing its input switch settings, and measuring its output voltage with the multi-meter, demonstrate that the logic circuit functions properly.

Post-Lab Exercises

Post-Lab Exercises 1-1 through 1-3 explore the characterization of a network by its Thevenin and Norton equivalents. Post-Lab Exercises 1-4 and 1-5 explore the static behavior of MOSFETS and logic gates.

- (1-1) Refer to your measurements from In-Lab Exercise 1-2; note that these measurements are the Thevenin equivalent voltage and Norton equivalent current of the network in Figure 4. From these measurements, compute the Thevenin/Norton equivalent resistance of the network. Compare the experimental Thevenin/Norton parameters to their corresponding values from Pre-Lab Exercise 1-2, and explain any discrepancies. Hint: consider measurement error and resistance variation.
- (1-2) Refer to your measurements from In-Lab Exercise 1-3. For each combination of resistor and voltage measurement, calculate the corresponding port current i.
- (1-3) Using the open-circuit voltage and short-circuit current measured during In-Lab Exercise 1-2, graph the *i-v* relation for the network. On this graph also plot the *i-v* data obtained by combining the voltages measured during In-Lab Exercise 1-3 and the currents calculated during Post-Lab Exercise 1-2. Explain any discrepancies between the measured *i-v* data and the *i-v* relation obtained from the Thevenin/Norton parameters.
- (1-4) Consult Figures 1 and 2 of the MOSFET data sheet and determine $R_{\rm DS-ON}$ and $v_{\rm T}$, respectively. Compare these to the values you measured during In-Lab Exercises 1-5 and 1-4, respectively.
- (1-5) Using the value of $R_{\rm DS-ON}$ measured during In-Lab Exercise 1-5, re-calculate the output voltages calculated in Pre-Lab Exercise 1-3. Explain any discrepancies between the re-calculated output voltages and those measured during In-Lab Exercises 1-6 through 1-8.

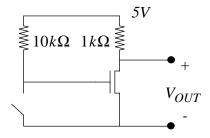


Figure 6: experimental NOT gate.